

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) POU920030178US1		Application Number NYA		
				Applicant(s) Motika, et al.				
				Filing Date NYA		Group Art Unit NYA		
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
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PC	2	4,503,537	03-05-1985	McAnney	371	25	11-08-1982	
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							YES	NO
PC	12	JP8005711A	1996-01-12	Japan	G01R31	28		✓
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
PC		W.H. Mcanney and J. Savir, "Built-In Checking of the Correct Self-Test Signature", September 1988, IEEE Transactions on Computers, Vol. 37, No. 9, pp. 1142-1145						
PC		J. Savir and William H. McAnney, "A Multiple Seed Linear Feedback Shift Register", February 1992, IEEE Transactions on Computers, Vol. 41, No. 2, pp. 250-252						
EXAMINER /Phung Chung/				DATE CONSIDERED 12/06/2006				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

